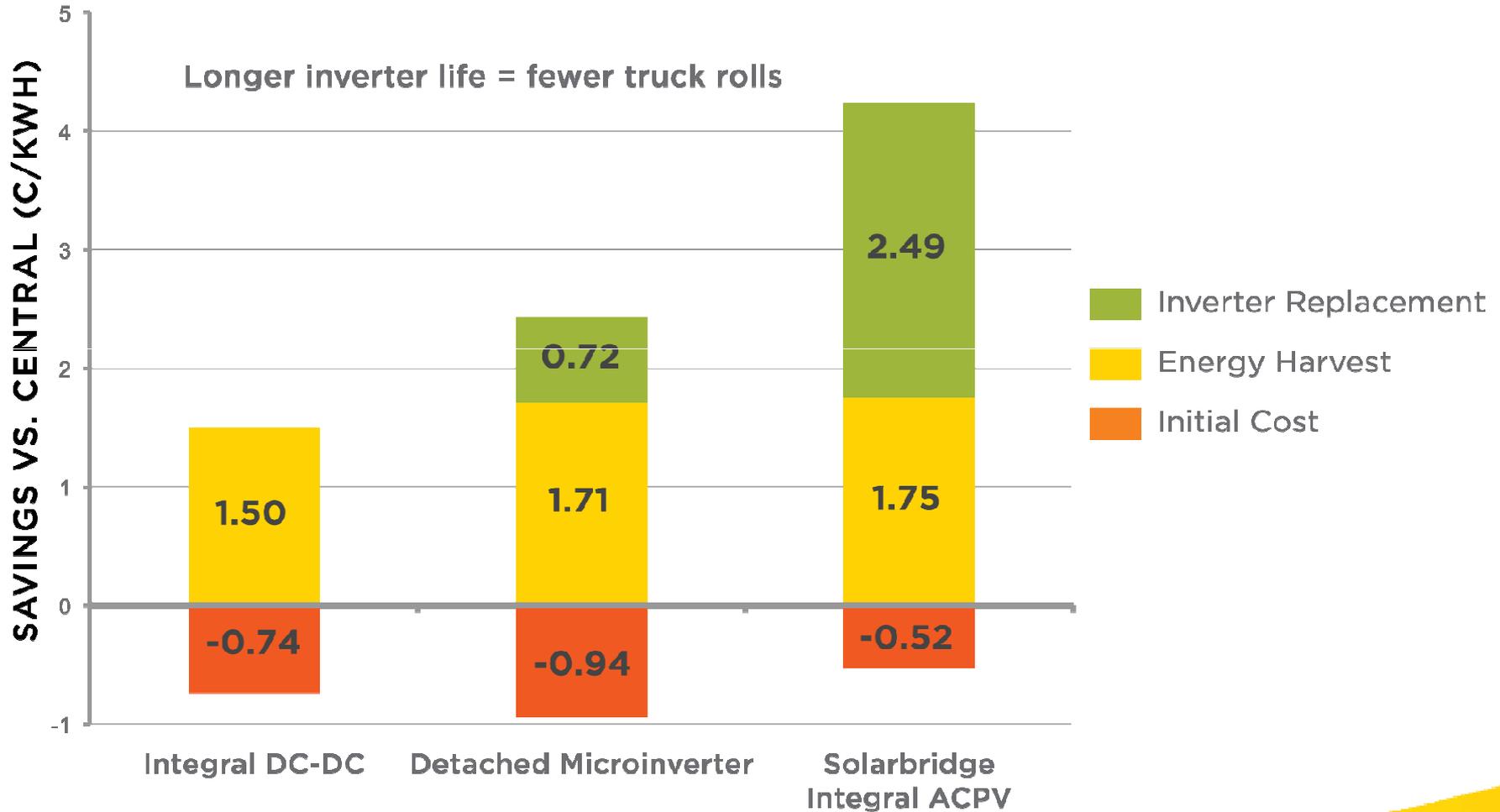


# PV-INTEGRATED MICROINVERTERS IN HIGH-RELIABILITY ROOFTOP APPLICATIONS

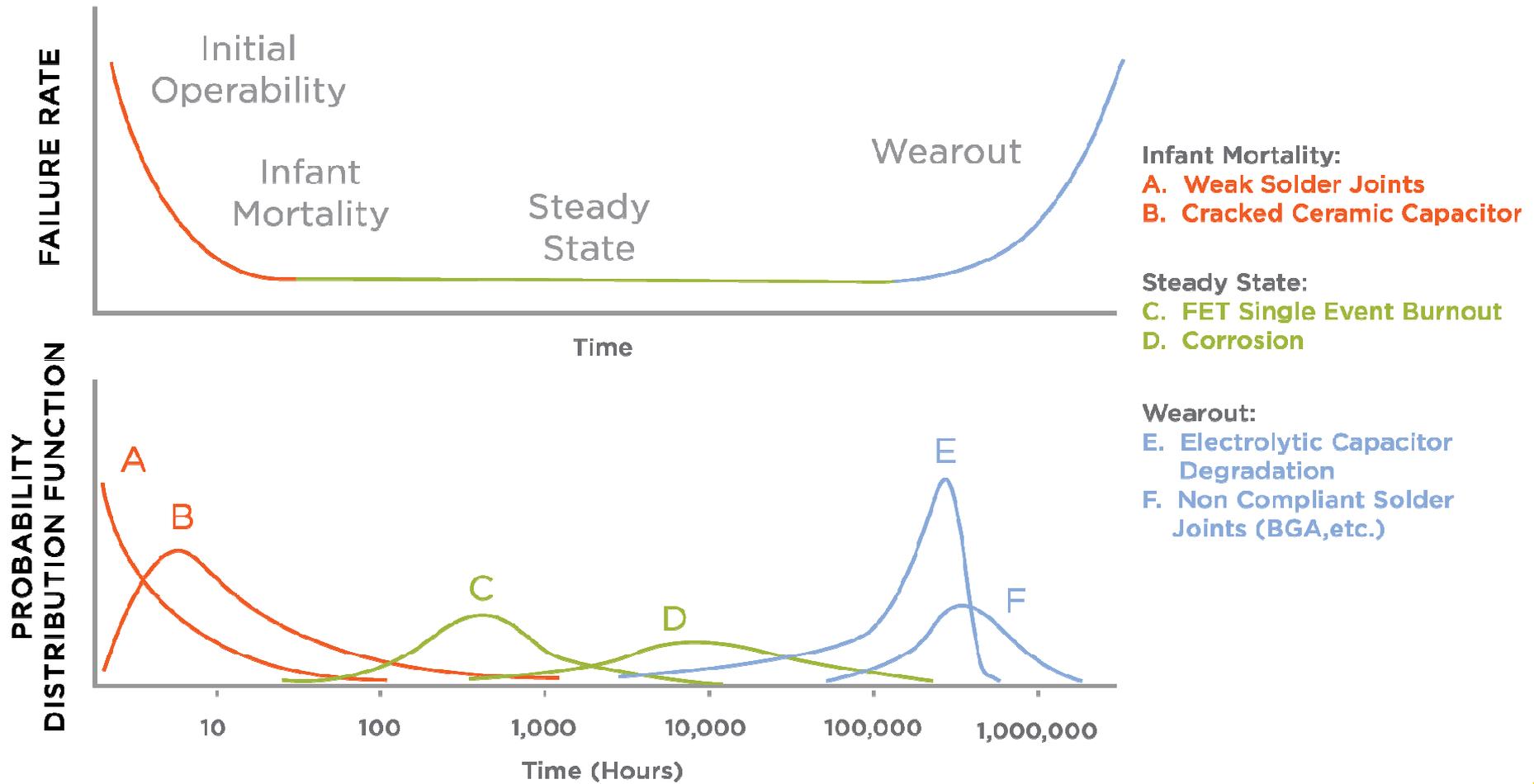
T. Paul Parker, Director of Product Qualification and Reliability



# INTEGRAL ACPV: HIGHER RELIABILITY, LOWER LCOE



# THE TRADITIONAL BATHTUB CURVE



# DEFINING RELIABILITY: MTBF HAS NOTHING TO DO WITH LIFETIME

- MTBF only applies to useful life/steady state
- MTBF does not predict product wearout
- MTBF does not account for harsh use environments
- MTBF does not consider manufacturing variation

MTBF  $\neq$  Lifetime

# ACHIEVING 25-YEAR RELIABILITY

- Design For Reliability
- Test For Reliability
- Manufacture For Reliability

# DESIGN FOR RELIABILITY: ELIMINATE TOP 5 RELIABILITY RISKS

Do not use:

- Electrolytic Capacitors (E-Caps)
- Optical-isolators
- Tantalum Capacitors

Minimize stresses on:

- Printed Circuit Board Vias
- Solder Joints

# E-CAPS FAIL TO MEET PV RELIABILITY STANDARDS

## CAPACITOR OPERATING LIFE

CAPACITOR OPERATING LIFE		T operating (Cap Core)	
		60	70
Capacitor Description	End of Life Failure Criteria		
5,000 Hour, 105C Rated e-caps	20% drop in Cap or 2x ESR	<b>8 Years</b>	<b>4</b>
10,000 Hour, 105C Rated e-caps	20% drop in Cap or 2x ESR	<b>16</b>	<b>8</b>
Film Capacitor (Industry Model)	20% drop in Cap	<b>1540</b>	<b>770</b>
VOLTAGE DERATING = 80% in all cases			

## STEADY STATE FAILURE RATE (FIT)

Capacitor Description	Bellcore	CNET	HRD4	M217	Siemens
Aluminum Electrolytic Capacitor	<b>210</b>	<b>22</b>	<b>120</b>	<b>16</b>	<b>120</b>
Film Capacitor	<b>17</b>	<b>4</b>	<b>6</b>	<b>1</b>	<b>14</b>
Fit Ratio E-Cap / Film	<b>12.4</b>	<b>5.5</b>	<b>20.0</b>	<b>16.0</b>	<b>8.6</b>

**Bellcore:** Similar to Telcordia SR-332

**CNET:** National Center for Telecommunications Studies

**HRD4:** Handbook of Reliability Data – Issue 4

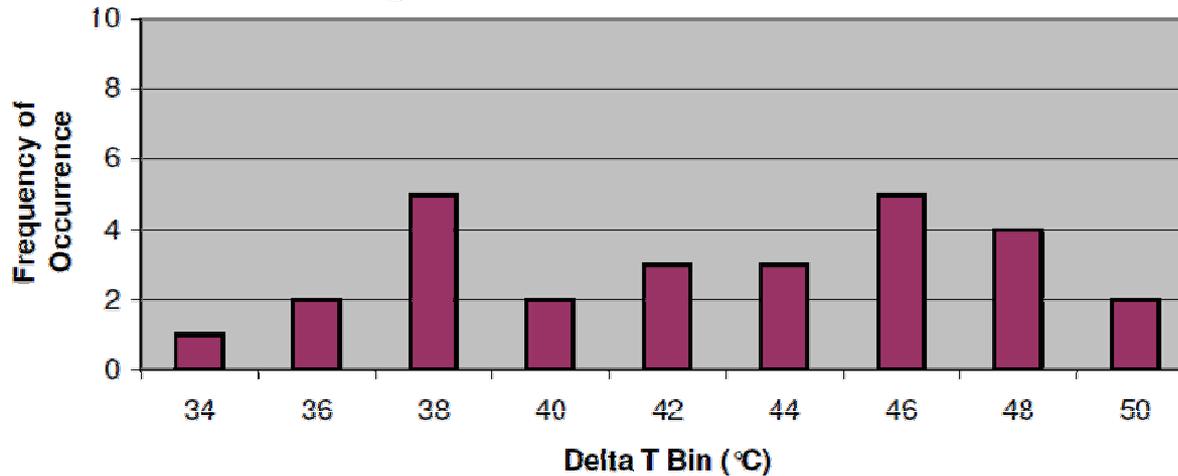
**M217:** MIL HDK-217

**Siemens:** SN29500

Ref: Jones, et.al., “A comparison of Electronic Reliability Prediction Methods”, IEEE Trans. On Reliability, June 1999, p. 127-143.

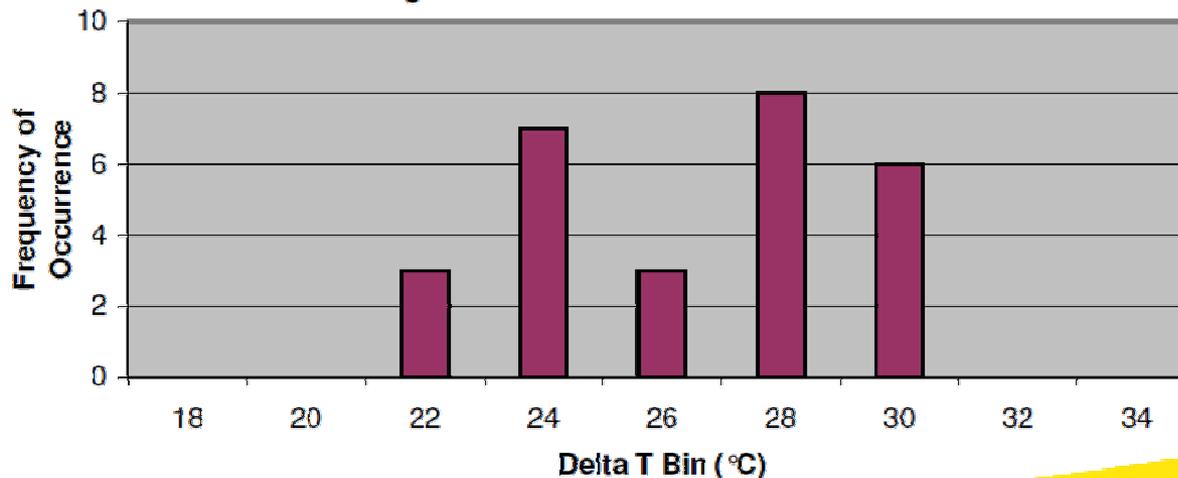
# SUMMER/WINTER DESERT TEMPERATURE DATA

## Histogram of Inverter Summer Delta T

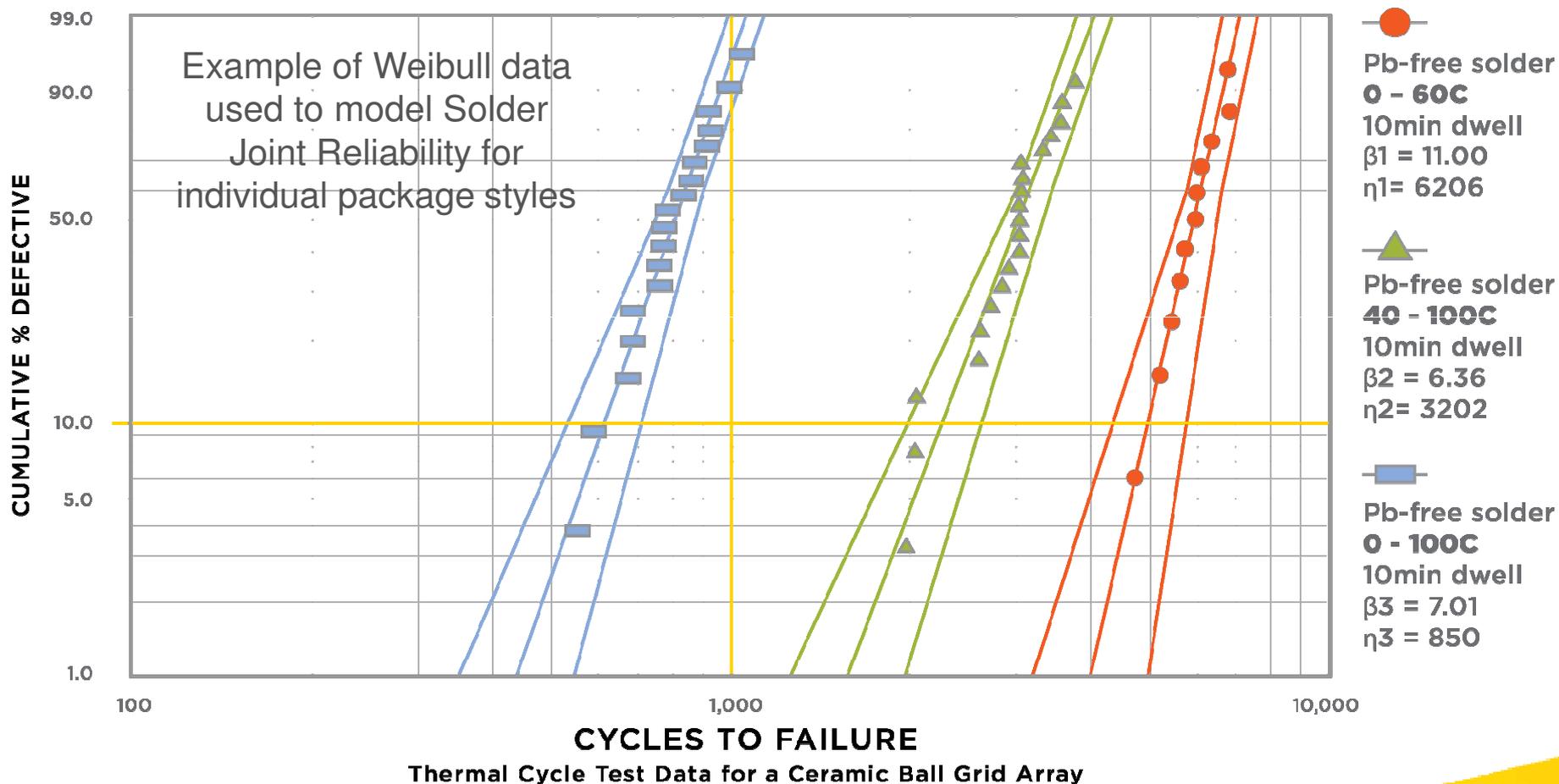


Component Daily  $\Delta T$  statistics are applied to fatigue models to predict time to wearout

## Histogram of Inverter Winter Delta T



# ACCELERATED TESTING: SOLDER JOINT RELIABILITY ACCELERATED WEIBULL ANALYSIS



Pan, et.al., "An Acceleration Model for Sn-Ag-Cu Solder Joint Reliability Under Various Thermal Cycle Conditions.", 2005 SMTAI, pp. 876-883.

# PREDICTING TIME TO WEAROUT

